

# Cavity Ring-Down Spectroscopy Measurements of Trace H<sub>2</sub>S in SF<sub>6</sub> and SF<sub>6</sub>/N<sub>2</sub> Mixture

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**Abstract:** H<sub>2</sub>S is one of the most important characteristic decomposition components of SF<sub>6</sub> insulated gas, and the detection of trace H<sub>2</sub>S is significant for early fault diagnosis of gas insulated electrical equipment. A 1 578 nm wavelength distributed feedback diode laser (DFB-DL) based cavity ring-down spectroscopy (CRDS) experimental platform is developed to monitor the concentrations of H<sub>2</sub>S in SF<sub>6</sub> and SF<sub>6</sub>/N<sub>2</sub> mixture carrier gas. The detection sensitivity is higher than  $1 \times 10^{-6}$ . The absorption cross section parameter  $\sigma$  is vital for calculating the concentration. With repeated experiments using standard gas samples, parameter  $\sigma$  of H<sub>2</sub>S in pure SF<sub>6</sub> and SF<sub>6</sub>/N<sub>2</sub> mixture carrier with different mixing ratios is calibrated. Compared with the simulated  $\sigma$  values, the influence of carrier gas on the broadening of spectral profile is discussed. The variation of absorption cross section  $\sigma$  with different carrier gas mixing ratios is studied as well, so that the calculation of the concentration in the carrier gas of any mixing ratio is possible. Thus, the application of CRDS in trace component detection of gas insulated electrical equipment is promising.

**Key words:** cavity ring-down spectroscopy (CRDS); absorption cross section; H<sub>2</sub>S; SF<sub>6</sub> decomposition component

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## 0 Introduction

Due to the excellent insulation and arc extinguishing performance, SF<sub>6</sub> and its mixed gas insulated electrical equipment cover almost the whole power transmission and transformation field and occupies an absolute dominant position. However, during the process of production, operation and maintenance, insulation defects such as burrs, free metal particles and suspended potential will inevitably appear in the SF<sub>6</sub> insulated electrical equipment. With the extension of operation time and the improvement of voltage level, the extremely uneven electric field reasoned by internal defects of SF<sub>6</sub> gas insulated switchgear will cause partial discharge (PD), which make SF<sub>6</sub> decompose into low fluorine sulfur compounds and then react with trace water and oxygen to form a range of decomposition products, including CO, CO<sub>2</sub>, CF<sub>4</sub>, C<sub>2</sub>F<sub>6</sub>, SOF<sub>2</sub>, SO<sub>2</sub>F<sub>2</sub>, SO<sub>2</sub>,

H<sub>2</sub>S, CS<sub>2</sub> and so on<sup>[1-2]</sup>. As this process induces further insulation deterioration, the safe operation of the whole power grid will be threatened as well.

In order to monitor the insulation status of SF<sub>6</sub> insulated electrical equipment<sup>[3-4]</sup>, the electrical method such as ultrasonic and UHF measurement of partial discharge and chemical diagnosis method based on the characteristic decomposition products of partial discharge SF<sub>6</sub> have been widely used in China's power grid<sup>[5-6]</sup>. Unlike electrical methods which directly measures signal of PD, chemical method as an indirect way of defect analysis applies gas analysis equipment of great sensibility and accuracy, real-time is also necessary, otherwise the fault early warning will be impossible.

H<sub>2</sub>S is one of the characteristic products of SF<sub>6</sub><sup>[7]</sup> and acts as a sign of high energy partial discharge<sup>[8]</sup>. With its extremely low concentration distribution (usually lower than  $1 \times 10^{-5}$ ), the detec-

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tion device must be online and sensitive with particularly low detection limit.

Traditional way of detection, for example, GC-MS, is able to analyze the concentration of nearly all kinds of SF<sub>6</sub> decomposition products. However, the long injection time prevents it to be an online equipment; a variety of sensing detection methods<sup>[9-11]</sup> are introduced as well, the sensors can detect most carbonaceous components of SF<sub>6</sub> decomposition products<sup>[12]</sup>, but for the sulfur-containing components SO<sub>2</sub>, SOF<sub>2</sub>, SO<sub>2</sub>F<sub>2</sub> and H<sub>2</sub>S, there are still knotty problems such as difficult desorption and long recovery time for carbon and semiconductor metal oxide sensors; Spectral methods<sup>[13]</sup> like ultraviolet fluorescence, cavity ring-down spectroscopy (CRDS)<sup>[14]</sup> and photoacoustic spectroscopy possess characteristics of high precision and stability, and they are coming into the sight of researchers. Among them, CRDS is a kind of extremely sensitive spectroscopy detection method<sup>[15-16]</sup>. As it measures the ring-down time of the laser in optical resonator instead of the light intensity, the results of the inversed concentration are anti-fluctuation of light source. Today with the advantages of high sensibility and precision, ability of real-time detection as well as no calibration required, CRDS has been widely used in field of atmospheric environmental science, biomedical science, semiconductor industry and other emerging areas.

Thus, the application of CRDS in detection of decomposition products of SF<sub>6</sub> in power equipment would be a practical innovation, where the decomposition component concentration is very low. To realize the detection of trace H<sub>2</sub>S component in pure SF<sub>6</sub>, a precise experimental platform is built to acquire the ring-down time in μs, experiments are carried out with standard gas, so that the vital absorption cross section parameters are calibrated and compared with the simulation results.

In order to deal with carbon peak and neutralization strategy, it is a trend to replace pure SF<sub>6</sub> with SF<sub>6</sub>/N<sub>2</sub> mixture to save the amount of SF<sub>6</sub>, because it will cause serious greenhouse effect. For this reason, this paper also discusses the inversion of H<sub>2</sub>S concentration in SF<sub>6</sub>/N<sub>2</sub> mixture as a func-

tion of mixing ratio.

## 1 Experiments

### 1.1 Experimental techniques

A simple ring-down cavity can be constructed by a pair of high-reflection mirrors (as shown in Fig.1), the reflectivity of which should be over 99.99%, so that the laser reflects thousands of times within the two mirrors before the its intensity attenuate in index to a certain threshold. The attenuation of which follows the Lambert-Beer law

$$I = I_0 e^{-\alpha l} \quad (1)$$

where  $I_0$  and  $I$  represent the initial intensity and the transmission intensity after being absorbed by the passing medium gas, respectively.  $\alpha$  is the absorption coefficient and  $l$  the effective absorption length.

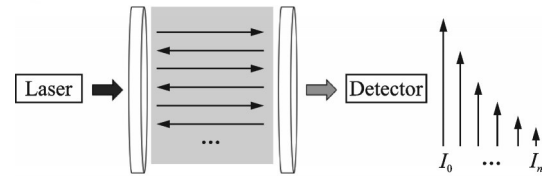


Fig.1 Schematic of absorption spectrum

The ring-down time without absorption sample is denoted as  $\tau_0$ , which represents the interval in which the initial intensity  $I_0$  attenuates to its  $1/e$ . Due to the fingerprint absorption characteristics of spectrum, only the laser of particular wavelength can be absorbed by the gas sample, and the ring-down time will be reduced to  $\tau$ . The sample concentration can thus be inversed with the following formula

$$N = \frac{1}{c\sigma(\nu)} \left( \frac{1}{\tau} - \frac{1}{\tau_0} \right) \quad (2)$$

where  $N$  is the molecular number density,  $c$  the light velocity in vacuum and  $\sigma(\nu)$  the sample absorption cross section.

### 1.2 CRDS experimental setup

The configuration of the experimental setup is shown in Fig.2.

The light source is a distributed feedback diode laser (DFB-DL) with fiber coupling output, and the central wavelength is 1 578 nm, which corre-

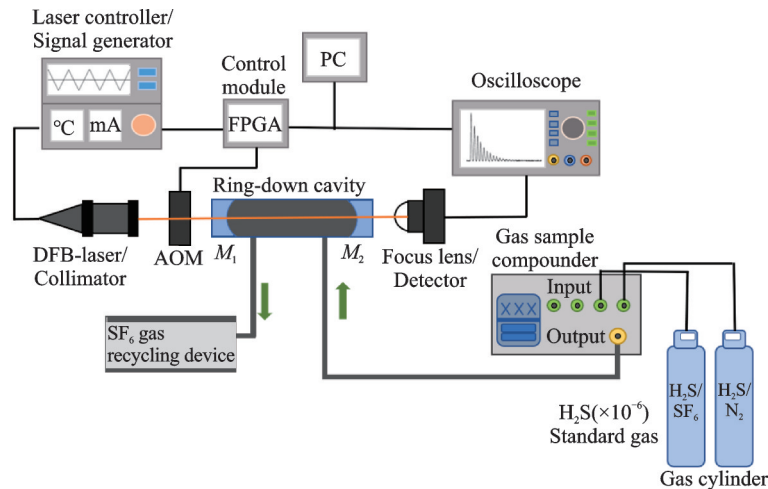
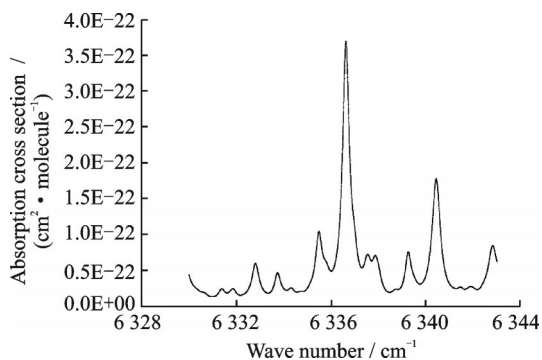


Fig.2 Schematic of CRDS experimental instrument

sponds to the obvious absorption peak around wave-number  $6\,337\text{ cm}^{-1}$  (as shown in Fig.3). The wavelength of DFB-DL is adjusted with laser controller in Fig.2 by controlling current or temperature. The current should be in range of 30—50 mA, and the thermistor resistance is set to 10 k $\Omega$  (ambient temperature). The acousto-optic modulator (AOM) in the optical path is to cut off the laser source through frequency shift under the control of FPGA module. To ensure that the incident laser is coupled into the ring-down cavity, which is composed of a pair of high reflection mirrors  $M_1$  and  $M_2$  as shown in Fig.2, it is necessary to realize stable frequency matching: A triangular wave current modulation signal is loaded on the laser controller through the signal generator, with a modulation frequency of 10 Hz and an amplitude of about 50 mV. The laser beam is coupled into the ring-down cavity through collimator and optical isolator, it is added to suppress optical feedback, which may destroy the mode matching of laser and resonator.

Fig.3 Absorption cross section of pure H<sub>2</sub>S (296 K, 1 atm)

After the transmitted light passing through the second high-reflection mirror  $M_2$ , it is received by the photodetector focusing lens and collected by the oscilloscope as well as the main FPGA control module. When the transmission intensity reaches the trigger threshold, a trigger signal is generated and sent to the laser controller to turn off the laser source. The ring-down events are thus formed and the ring-down curve is recorded for subsequent data processing.

The experimental gases are standard, which are pumped into the resonant cavity after being prepared by the gas distributor. The mass flowmeter in the gas sample compounder is used to accurately monitor the outlet flow and the waste gas is recovered by special recovery device.

## 2 Experiment Results and Discussion

### 2.1 Measurements under pure carrier gas

With the experimental platform the ring-down time  $\tau$  is accessible, according to Eq.(2), the absorption cross section  $\sigma(\nu)$  is necessary to calculate the concentration. The convenient and widely used way is to get the  $\sigma(\nu)$  from online simulation<sup>[14-17]</sup> with data of HITRAN<sup>[18-19]</sup>, which is the abbreviation of high-resolution transmission molecular absorption database. It is one of the most used spectral databases in infrared spectroscopy. It is widely used for query or comparison of infrared spectral data.

The simulation results are shown in Fig. 3, the profile chosen is Voigt, as the pressure 1 atm is not so high to fit Gaussian profile. The central wavenumber of the chosen peak is  $6\,336.62\text{ cm}^{-1}$ , the absorption cross section of this main absorption peak  $\sigma(\nu=6\,336.62\text{ cm}^{-1})$  is  $3.692\times 10^{-22}\text{ cm}^2/\text{molecule}$ .

In order to precisely detect the concentration of the trace  $\text{H}_2\text{S}$  in  $\text{SF}_6$  gas insulated electrical equipment, the absorption cross section  $\sigma(\nu)$  of  $\text{H}_2\text{S}$  in pure  $\text{SF}_6$  should be calibrated. Firstly  $1\times 10^{-5}$   $\text{H}_2\text{S}$  standard gas in pure  $\text{SF}_6$  ( $1\times 10^{-5}$   $\text{H}_2\text{S}/\text{SF}_6$  in following) is pumped into the device at a flow rate of 200 ml/min. After taking the average value of multiple measurements, the ring-down time  $\tau$  and the base line  $\tau_0$  of the spectrum are put into Eq. (3) to calculate the experimental value of  $\sigma(\nu_0)$ .

$$\sigma(\nu_0) = \frac{1}{cN} \left( \frac{1}{\tau} - \frac{1}{\tau_0} \right) \quad (3)$$

$$N = \frac{n(\times 10^{-6}) \cdot N_A}{22.4 \times 10^9} \quad (4)$$

where  $\nu_0$  is the center wavenumber automatically located by program scanning,  $N_A$  the Avogadro constant, and  $n(\times 10^{-6})$  the concentration parts per

million. In case of  $1\times 10^{-5}$   $\text{H}_2\text{S}/\text{SF}_6$   $\sigma(\nu_0)$  is calculated  $6.293\times 10^{-22}\text{ cm}^2/\text{molecule}$ , then the  $5\times 10^{-5}$   $\text{H}_2\text{S}/\text{SF}_6$  standard gas is tested as above and the average value  $\sigma(\nu_0)$  of multiple measurements turns out to be  $6.367\times 10^{-22}\text{ cm}^2/\text{molecule}$ , which can be considered to be consistent within the allowable error range. Thus, the  $\sigma(\nu_0)$  of trace  $\text{H}_2\text{S}$  ( $\times 10^{-6}$  level) in pure  $\text{SF}_6$  can be averaged as  $6.330\times 10^{-22}\text{ cm}^2/\text{molecule}$ , and this value is very different from the simulation value ( $3.692\times 10^{-22}\text{ cm}^2/\text{molecule}$ ). To compare the experimental calibration absorption cross section and the simulated one,  $1\times 10^{-5}$   $\text{H}_2\text{S}/\text{SF}_6$  standard gas is diluted by  $\text{SF}_6$  purified gas to  $8\times 10^{-6}$ ,  $5\times 10^{-6}$ ,  $2\times 10^{-6}$ , respectively. As shown in the column "Trace  $\text{H}_2\text{S}/\text{pure SF}_6$ " of Table 1, the "Raw value" and corrected ones share the same ring-down time  $\tau$  and  $\tau_0$ , but "Raw value" is calculated with simulated  $\sigma(\nu_0)$ , and the "Correction value" with experimental calibrated  $\sigma(\nu_0)$ . Obviously, the deviation of simulation value is so large that the simulation method is almost invalid under this circumstance. Reasons can be traced back to the line broadening theory<sup>[20]</sup>.

**Table 1 Concentration correction with experimental calibrated absorption cross section**

Concentration/ $10^{-6}$	Trace $\text{H}_2\text{S}/$ pure $\text{SF}_6$			Trace $\text{H}_2\text{S}/$ 80% $\text{SF}_6$ , 20% $\text{N}_2$			Trace $\text{H}_2\text{S}/$ 50% $\text{SF}_6$ , 50% $\text{N}_2$			Trace $\text{H}_2\text{S}/$ 20% $\text{SF}_6$ , 80% $\text{N}_2$		
	8	5	2	8	5	2	8	5	2	8	5	2
Raw value with simulated $\sigma(\nu_0)$	13.666	8.642	3.613	5.181	3.364	1.391	2.786	2.148	0.979	2.825	1.705	0.637
Raw deviation	5.666	3.642	1.613	-2.819	-1.636	-0.609	-5.214	-2.852	-1.021	-5.175	-3.295	-1.363
Correction value	7.971	5.041	2.108	7.638	5.021	2.087	6.666	5.025	2.322	8.432	5.037	1.874
Correction deviation	-0.029	0.041	0.108	-0.362	0.021	0.087	-1.334	0.025	0.322	0.432	0.037	-0.126

In fact, the energy level of an atom is not a line without width, but has a certain frequency width. Due to various factors<sup>[21-22]</sup> (for example, natural broadening, collision broadening, Doppler broadening, etc.), the power (i.e., light intensity) of spontaneous emission/absorption is distributed in a small frequency range centered on its transition Bohr frequency  $\nu$ .

$$\nu = \frac{E_2 - E_1}{h} \quad (5)$$

When the frequency  $\nu$  of the luminous particles deviates from the center frequency, the monochromatic light power will decay according to a certain

law (profile)<sup>[23]</sup>, as shown in Fig. 4. And  $\nu_0$  is the center frequency.

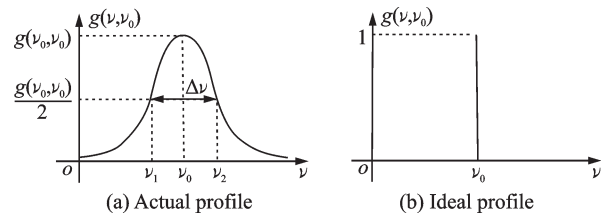


Fig. 4 Spectral line broadening

The absorption cross section is proportional to the spectral profile  $g(\nu)$  and absorption line strength  $S$ , which is only related to temperature and species,

and can be written as a function of temperature. It means at room temperature the line strength  $S$  of the target gas H<sub>2</sub>S is constant. However, different carrier gas composition and their mixing ratio will affect the broadening mechanism of the spectral line, change the full width at half maximum (FWHM)  $\Delta\nu$  of the profile and the function value at the central wavelength  $\nu_0$ , so as to alter the absorption cross section  $\sigma(\nu_0)$ . The simulation is based on HITRAN database, which only involves the broadening effect of air and H<sub>2</sub>S molecules to itself, instead of the broadening effect from the carrier gas SF<sub>6</sub> or the mixed carrier gas SF<sub>6</sub>/N<sub>2</sub>. Therefore, the simulation values in this case will cause large deviation, and the absorption cross section calibrated with standard gas is surely more accurate. At the same time, these calibrated  $\sigma(\nu_0)$  also fill a tiny part of blank in the database and provide a reference for the application of CRDS in the detection of SF<sub>6</sub> decomposition components.

## 2.2 Measurements under mixed carrier gas

To calculate the concentration of trace H<sub>2</sub>S in mixed carrier gas, standard gas with different mixing ratio of carrier is prepared and tested repeatedly to calibrate the adsorption cross section value shown in Fig.5.

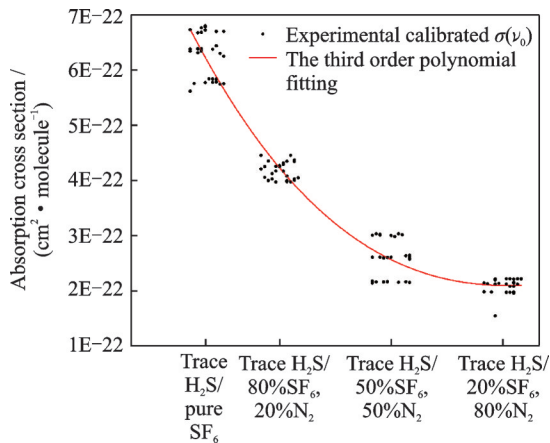


Fig.5 Variation of absorption cross section with carrier gas mixing ratio (trace H<sub>2</sub>S in SF<sub>6</sub>/N<sub>2</sub> mixture)

As the polynomial fitting curve shown in Fig.5, with the increase of the proportion of mixed nitrogen, the decrease of the  $\sigma(\nu_0)$  reveals a certain regularity. Set the fitting polynomial order to 3, the ana-

lytical formula is

$$y = [2.21275 + (-1.18092)x + 2.32619x^2 + 2.86614x^3] \times 10^{-22} \quad (6)$$

where  $y$  is the central peak absorption cross section  $\sigma(\nu_0)$ , and  $x$  the proportion of SF<sub>6</sub> ( $x=1$  for pure SF<sub>6</sub> carrier). To verify the validity of the above formula, the H<sub>2</sub>S in the mixed carrier gas is reconfigured with the gas distributor and the concentrations are inversed with the fitted cross section data, which form the correction values in Table 1 (the rest columns). The correction data is evidently much closer to the preparation standard value, and the concentrations inversed can be determined quantitatively at a precision better than  $1 \times 10^{-6}$ . With the subsequent verification, if the formula is applicable to other mixing ratios, the trace component detection in the case of mixed carrier gas will not need to be calibrated over and over.

## 3 Conclusions

An experimental platform of cavity ring-down instrument based on diode lasers using the 1578 nm absorption band of H<sub>2</sub>S was developed for measurements of trace H<sub>2</sub>S in pure SF<sub>6</sub> and SF<sub>6</sub>/N<sub>2</sub> mixed carrier gas with different mixing ratio. After calibration of the absorption cross section  $\sigma(\nu_0)$  with trace H<sub>2</sub>S standard sample in carrier gas of SF<sub>6</sub> and its mixture with N<sub>2</sub>, the concentrations inversed can be determined quantitatively at a precision better than  $1 \times 10^{-6}$ . The corrected experimental  $\sigma(\nu_0)$  is much more accurate than the simulation value, and this result also supplements some data gaps in HITRAN database. The variation of absorption cross section with carrier gas mixing ratio was studied as well, which fits well with a third order polynomial, with which the calculation of concentration in carrier gas of any mixing ratio is possible. In the field of trace gas detection CRDS is outstanding with advantages of high sensibility and precision so on, with the study and conclusions in this paper and further, its application in trace decomposition component detection of SF<sub>6</sub> and its gas mixture insulated electrical equipment is well expectable.

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**Author contributions** Miss ZOU Keyuan designed this research, compiled the model, conducted the simulation and the experiments, analyzed the results, and wrote the manuscript. Prof. ZHANG Chaohai and Dr. ZHU Min contributed to the background and modification of the final paper. All authors commented on the manuscript draft and approved the submission.

**Competing interests** The author declares no competing interests.

(Production Editor: SUN Jing)

## 光腔衰荡光谱法检测 SF<sub>6</sub> 以及 SF<sub>6</sub>/N<sub>2</sub> 混合载气下的痕迹 H<sub>2</sub>S

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**摘要:** H<sub>2</sub>S 是六氟化硫绝缘气体最重要的特征组分之一, 痕迹 H<sub>2</sub>S 的检测对 SF<sub>6</sub> 气体绝缘电气设备的早期故障诊断具有重要意义。为监测 SF<sub>6</sub> 和 SF<sub>6</sub>/N<sub>2</sub> 混合载气中 H<sub>2</sub>S 的浓度, 本文研制了基于 1 578 nm 波长分布反馈二极管激光器 (Distributed feedback diode laser, DFB-DL) 的腔衰荡光谱 (Cavity ring-down spectroscopy, CRDS) 实验平台, 其检测灵敏度优于  $1 \times 10^{-6}$ 。吸收截面参数  $\sigma$  对于计算浓度至关重要, 使用标准气体样品进行重复实验, 标定了纯 SF<sub>6</sub> 和不同混合比的 SF<sub>6</sub>/N<sub>2</sub> 混合载气中 H<sub>2</sub>S 的  $\sigma$  参数, 并通过与  $\sigma$  仿真值的比较讨论了载气对谱线展宽的影响。研究了吸收截面  $\sigma$  参数随载气混合比的变化规律, 从而可以计算任意混合比载气下的目标气体浓度。由此, CRDS 在气体绝缘电气设备痕量成分检测中的应用前景十分可观。

**关键词:** 腔衰荡光谱; 吸收截面; H<sub>2</sub>S; SF<sub>6</sub> 分解组分